Identification of Functional Groups on the Surface of a Fluorinated Diamond Crystal by Photoelectron Spectroscopy

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Summary CF_3 , CF_2 , and CF surface groups formed when diamond is exposed to microwave-discharged SF_6 may be characterized and quantitatively estimated by X-ray photoelectron spectroscopy.

WE report the first unambiguous identification of functional groups, formed by the chemisorption of heteroatoms, on a single-crystal elemental carbon surface. Previous attempts¹⁻³ to characterize, by i.r. spectroscopy, vacuum thermogravimetry, electrochemical and classical, wetchemical methods, the nature of various adsorbed species on a wide range of carbons have been inconclusive. Moreover, where such techniques have achieved qualified success (as e.g., in the i.r. reflectance spectroscopic study of carbonoxygen surface complexes) it has been necessary to use solids possessing very large areas (typically 1200 m² g⁻¹ for a polyvinylidene chloride carbon³ and 20-200 m² g⁻¹ for diamond powder²). Because of its sensitivity, X-ray photoelectron spectroscopy (XPS) is capable of readily detecting submonolayer amounts of heteroatoms on very low area ($ca \ 0.5 \ cm^2$) solid surfaces. We have demonstrated elsewhere^{4,5} the merit of this technique for the elucidation of differences in adsorbability between the prismatic and basal faces of graphite.

The diamond single crystal, with (111) surface predominant, was 'saturated' with chemisorbed fluorine by exposing it to fluorine atoms⁶ generated in a quartz vessel by microwave-discharged (2450 MHz) SF₆ vapour at a pressure of 10^{-3} Torr for times ranging from a few minutes to several hours. A monolayer[†] of covalent fluoride formed (see below) in a few minutes, and it is probable that there is a good deal of concomitant gasification (just as with excited oxygen,^{5,7} also at room temperature, there is simultaneous



FIGURE 1. Typical XPS spectra [C(1s) region] of a diamond (111) face before and after exposure to fluorine atoms. Note production of high-B.E. satellites at *ca.* 3.1, 5.3, and 7.8 eV from main C(1s) (diamond) peak.

† A monolayer of the (111) face refers to half a single puckered-hexagon plane.

formation of stable surface oxide and gasification yielding volatile CO and CO₂).

The C(1s) region of the XP spectrum[‡] contains three satellites (Figure 1) at higher binding energy (B.E.) from the

Fluoromethanes (gaseous)	CH4	CFH3	CF_2H_2	CF₃ H	
	Ì	ŀ	I	l	
	с	CF	CF2	CF3	
Fluorinated diamono (111) face	I	ł	1	I	
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	0		5		1

Binding energy shift of C(1s) electrons / eV

10

FIGURE 2. Comparison of C(1s) B.E. shifts observed in the series CH₄, CH₃F, CH₂F₂, and CHF₃ (for isolated gas molecules)⁸ and the shifts measured here for fluorinated diamond.

main C(1s) diamond peak: these occur at ca 3.1, 5.3, and 7.8 eV, values which are close to the expected shifts for CF, CF_2 , and CF_3 groups on the basis of previous data⁸ for the C(1s) peaks in progressing along the series CH₄, CFH₃, CF₂H₂, and CF₃H (see Figure 2). Since the photoelectric crosssections of F(1s) and C(1s) for Mg- K_{α} (the X-ray radiation used here) are known,^{9,10} we may independently estimate, from the total observed C(1s) satellite peak intensity, the F(1s) intensity arising from the three fluorocarbon peaks. The computed figure tallies within 5% with the observed F(1s) peak intensity, thus confirming our assignments. Since the escape depth of diamond is also known¹¹ to be 2.4 +0.4 nm, we may compute that, after 20 min exposure to excited SF₆, an average thickness of some two monolayers of diamond is converted into fluorocarbon, 1.3 layers being composed of \geq CF groups, 0.6 of >CF₂, and 0.2 of -CF₃. (No sulphur, *i.e.* less than 0.03 monolayers, is chemisorbed). As gasification proceeds the total average thickness of surface fluoride increases only gradually, but the proportion of CF₂ continues to rise, a fact which is indicative of enhanced surface roughening since -CF₂ groups occur at ledge sites on (111) faces. The proportion of CF_3 groups, which would be favoured at kink sites, diminishes somewhat as reaction proceeds, but all such ratios are doubtless temperature and pressure sensitive. Fuller details of XPS studies of fluorinated diamond and graphite crystals, involving a variety of fluorinating agents, will be described elsewhere.

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[‡] Discharged SF₆ is too corrosive to be used *in situ* in the spectrometer chamber. Traces of oxygen are picked up by the diamond upon transfer to the spectrometer, but the presence of the oxygen (shown in the spectra) does not invalidate our conclusions.

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